

Quad, 16 Bit Dac with 10ppm/°C Max On-Chip Reference in 14-Lead TSSOP

Preliminary Technical Data

AD5666

FEATURES

Low Power Quad 16 Bit DAC
14-Lead TSSOP Package
On-chip 1.25/2.5V, 10ppm/°C Reference
Power-Down to 200 nA @ 5V, 50 nA @ 3V
3V/5V Power Supply
Guaranteed Monotonic by Design
Power-On-Reset to Zero or Midscale
Three Power-Down Functions
Hardware /LDAC and /CLR functions
SDO Daisy-Chaining Option
Rail-to-Rail Operation

APPLICATIONS

ProcessControl
Data Acquisition Systems
Portable Battery Powered Instruments

GENERAL DESCRIPTION

The AD5666 DAC is a low power, quad, 16-bit buffered voltage-out DAC. The part operates from a single +2.7V to +5.5V, and is guaranteed monotonic by design.

The AD5666 has an on-chip reference with an internal gain of two. The AD5666-1 has a 1.25V 10ppm/°C max reference giving a fullscale output of 2.5V and the AD5666-2 has a 2.5V 10ppm/°C max reference giving a fullscale output of 5V. The on-board reference is off at power-up allowing the use of an external reference. The internal reference is turned on by writing to the DAC.

The part incorporates a power-on-reset circuit that ensures that the DAC output powers up to zero volts (POR pin low) or midscale (POR pin high) and remains there until a valid write takes place. The part contains a power-down feature that reduces the current consumption of the device to 200nA at 5V and provides software selectable output loads while in power-down mode for any or all DACs channels.

Digital Gain and Offset Adjustment
Programmable Voltage and Current Sources
Programmable Attenuators

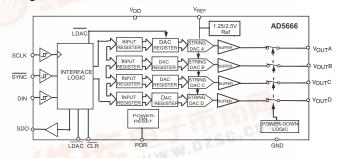


Figure 1. Functional Block Diagram

The outputs of all DACs may be updated simultaneously using the \overline{LDAC} function, with the added functionality of user selectable DAC channels to simultaneously \overline{LDAC} . There is also an asynchronous active low \overline{CLR} that clears all DACs to a software selectable code - 0 V, midscale or fullscale.

The AD5666 utilizes a versatile three-wire serial interface that operates at clock rates up to 50 MHz and is compatible with standard SPI™, QSPI™, MICROWIRE™ and DSP interface standards. Its on-chip precision output amplifier allows rail-to-rail output swing to be achieved.

PRODUCT HIGHLIGHTS

- 1. Quad 16-Bit DAC
- 2. On-chip 1.25/2.5V, 10ppm/°C max Reference.
- 3. Available in 14-lead TSSOP package.
- 4. Selectable Power-On-Reset to Zero volts or Midscale.
- 5. Power-down capability. When powered down, the DAC typically consumes 50nA at 3V and 200nA at 5V.

Preliminary Technical Data

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REVISION HISTORY

Revision 0: Initial Version

AD5666-SPECIFICATIONS

 $(V_{DD} = +4.5 \text{ V to } +5.5 \text{ V}; R_L = 2 \text{ k}\Omega \text{ to GND}; C_L = 200 \text{ pF to GND}; V_{REFIN} = \text{Vdd}; \text{all specifications } T_{MIN} \text{ to } T_{MAX} \text{ unless otherwise noted})$ Table 1.

		A Grade	9		
					B Version ¹ , ²
Parameter	Min	Тур	Max	Unit	Conditions/Comments
STATIC PERFORMANCE ^{3,4}					
Resolution	16			Bits	
Relative Accuracy			±32	LSB	See Figure 4
Differential Nonlinearity			±1	LSB	Guaranteed Monotonic by Design. See Figure 5.
Load Regulation			2	LSB/mA	VDD=Vref=5V, Midscale lout=0mA to 15mA sourcing/sinking
Zero Code Error		+1	+9	mV	All Zeroes Loaded to DAC Register. See Figure 8.
Zero Code Error Drift ³		±20		μV/°C	
Full-Scale Error	-0.15		-1.25	% of FSR	All Ones Loaded to DAC Register. See Figure 8.
Gain Error			±0.7	% of FSR	
Gain Temperature Coefficient		±5		ppm	of FSR/°C
Offset Error		±1	±9	mV	
Offset Temperature Coefficient		1.7		μV/°C	
DC Power Supply Rejection Ratio ⁶		-80		dB	V_{DD} $\pm 10\%$
DC Crosstalk ⁶		28		μV	$R_L = 2 \text{ k. to GND or } V_{DD}$
		3.5		μV/mA	Due to Load current change
		-7.3		μV	Due to Powering Down (per channel)
OUTPUT CHARACTERISTICS ⁶					
Output Voltage Range	0		V_{DD}	V	
Capacitive Load Stability		470		pF	R _L =∞
		1000		pF	$R_L=2 k\Omega$
DC Output Impedance		1		Ω	
Short Circuit Current		50		mA	V _{DD} =+5V
Power-Up Time		10		μs	Mode. V _{DD} =+5V
REFERENCE INPUTS ³					
Reference Input voltage		Vdd		V	±1% for specified performance
Reference Current		20	30	μΑ	$V_{REF} = V_{DD} = +5.5V$
Reference Input Range	0		$V_{\rm DD}$		
Reference Input Impedance		14.6		kΩ	Per Dac Channel
REFERENCE OUTPUT					
Output Voltage	2.495	2.5	2.505	V	
Reference TC			±10	ppm/°C	
Reference Output Impedance		2		kΩ	
LOGIC INPUTS ³					
Input Current			±1	μΑ	
•	<u> </u>			1 '	ı

 $^{^1}$ Temperature ranges are as follows: B Version: -40 $^{\circ}$ C to +125 $^{\circ}$ C, typical at 25 $^{\circ}$ C.

² Linearity calculated using a reduced code range of 485 to 64714. Output unloaded.

³DC specifications tested with the outputs unloaded unless stated otherwise.

⁴Linearity is tested using a reduced code range: AD5628 (Code 48 to Code 4047), AD5648 (Code / to Code /), and AD5668 (Code 485 to 64714). ⁶Guaranteed by design and characterization; not production tested.

⁸Interface inactive. All DACs active. DAC outputs unloaded.

⁹All eight DACs powered down.

Specifications subject to change without notice.

Preliminary Technical Data

		A Grad	e		
Parameter	Min	Тур	Max	Unit	B Version ¹ , ² Conditions/Comments
V _{INL} , Input Low Voltage			0.8	V	V _{DD} =+5 V
V _{INH} , Input High Voltage	2			V	V _{DD} =+5 V
Pin Capacitance		3		pF	
LOGIC OUTPUTS (SDO) ³					
Output Low Voltage, Vol			0.4	V	Isink = 2 mA
Output High Voltage, Vон	V DD - 1				Isource = 2 mA
High Impedance Leakage Current			±1	μΑ	
High Impedance Leakage Current		5		pF	
POWER REQUIREMENTS					
V_{DD}	4.5		5.5	V	All Digital Inputs at 0 or V _{DD}
					DAC Active and Excluding Load Current
I _{DD} (Normal Mode) ⁸					V _{IH} =V _{DD} and V _{IL} =GND
V_{DD} =4.5 V to +5.5 V		0.7	1	mA	Internal Reference Off
V_{DD} =4.5 V to +5.5 V		2	2.5	mA	Internal Reference On
I _{DD} (All Power-Down Modes) ⁹			1	μΑ	V _{IH} =V _{DD} and V _{IL} =GND
POWER EFFICIENCY					
I _{OUT} /I _{DD}		89		%	I _{LOAD} =2 mA, V _{DD} =+5 V

 $\textbf{AC CHARACTERISTICS}^{1} \ \, (V_{DD} = +4.5 \ V \ to \ +5.5 \ V; \ R_{L} = 2 \ k\Omega \ to \ GND; \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ specifications \ C_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ V_{REFIN} = Vdd; \ all \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L} = 200 \ pF \ to \ GND; \ S_{L}$

T_{MIN} to T_{MAX} unless otherwise noted)

Parameter ²	Min	Тур	Max	Unit	B Version ¹ Conditions/Comments
Output Voltage Settling Time					
AD5666		8	10	μs	1/4 to 3/4 scale settling to ±2LSB
Settling Time for 1LSB Step					
Slew Rate		1		V/µs	
Digital-to-Analog Glitch Impulse		10		nV-s	1 LSB Change Around Major Carry. See Figure 21.
Reference Feedthrough		100		dB	
SDO Feedthrough		4		nV-s	Daisy Chain Mode; SDO Load is 10pF
Digital Feedthrough		0.5		nV-s	
Digital Crosstalk		0.5		nV-s	
Analog Crosstalk		1		nV-s	
DAC-to-DAC Crosstalk		3		nV-s	
Multiplying Bandwidth		200		kHz	$VREF = 2V \pm 0.1 V p-p.$
Total Harmonic Distortion		-80		dB	$VREF = 2V \pm 0.1 V p-p.$ Frequency = 10kHz
Output Noise Spectral Density		120		nV/√Hz	DAC code=8400 _H , 1kHz
		100		nV/√Hz	DAC code=8400 _H , 10kHz
Output Noise		15		μVр-р	0.1Hz to 10Hz;

¹Guaranteed by design and characterization; not production tested.

²See the Terminology section.

³Temperature range (Y Version): -40°C to +125°C; typical at +25°C.

Specifications subject to change without notice.

AD5666-SPECIFICATIONS

 $(V_{DD} = +2.7 \text{ V to } +3.6 \text{ V}; R_L = 2 \text{ k}\Omega \text{ to GND}; C_L = 200 \text{ pF to GND}; External VREF = Vdd; all specifications } T_{MIN} \text{ to } T_{MAX} \text{ unless otherwise noted})$

Table 1

		A Grad	e		
					B Version ¹ , ¹
Parameter	Min	Тур	Max	Unit	Conditions/Comments
STATIC PERFORMANCE ^{3,4}					
Resolution	16			Bits	
Relative Accuracy			±32	LSB	See Figure 4
Differential Nonlinearity			±1	LSB	Guaranteed Monotonic by Design. See Figure 5.
Load Regulation			4	LSB/mA	VDD=Vref=3V, Midscale lout=0mA to 7.5mA sourcing/sinking
Zero Code Error		+1	+9	mV	All Zeroes Loaded to DAC Register. See Figure 8.
Zero Code Error Drift ¹		±20		μV/°C	
Full-Scale Error	-0.15		-1.25	% of FSR	All Ones Loaded to DAC Register. See Figure 8.
Gain Error			±0.7	% of FSR	
Gain Temperature Coefficient		±5		ppm	of FSR/°C
Offset Error		±1	±9	mV	
Offset Temperature Coefficient		1.7		μV/°C	
DC Power Supply Rejection Ratio ⁶		-80		dB	V _{DD} ±10%
DC Crosstalk ⁶		28		μV	$R_L = 2 \text{ k. to GND or } V_{DD}$
		3.5		μV/mA	Due to Load current change
		-7.3		μV	Due to Powering Down (per channel)
OUTPUT CHARACTERISTICS ⁶		7.5			
Output Voltage Range	0		V_{DD}	V	
Capacitive Load Stability		470	♥ DD	pF	R _L =∞
capacitive Load Stability		1000		pF	$R_L=2 k\Omega$
DC Output Impedance		1		Ω	11, 21,122
Short Circuit Current		20		mA	V _{DD} =+3V Coming Out of Power-Down
Power-Up Time		10		ms	Mode. V _{DD} =+3V
REFERENCE INPUTS ³				1113	Model VBB 13V
Reference Input voltage		Vdd		V	±1% for specified performance
Reference Current		35	45	μΑ	$V_{REF} = V_{DD} = +3.6V$
Reference Input Range	0	33	V_{DD}	M 11	VALE VED 13.5 V
Reference Input Impedance		14.6	• 55	kΩ	Per Dac Channel
REFERENCE OUTPUT		11.0		K32	Ter Due Chamer
Output Voltage	1.248	1.25	1.252	V	
Reference TC	1.2 10	1.23	±10	ppm/°C	
Reference Output Impedance		2		kΩ	
LOGIC INPUTS ³				102	
Input Current			±1	μΑ	
V _{INL} , Input Low Voltage			0.8	V	V _{DD} =+3 V
V _{INH} , Input High Voltage	2			V	$V_{DD}=+3 V$
Pin Capacitance		3		pF	
LOGIC OUTPUTS (SDO) ³					
Output Low Voltage, Vol.			0.4	V	Isink = 2 mA

Output High Voltage, Vон	VDD - 0.5				Isource = 2 mA
High Impedance Leakage Current			±1	μА	
High Impedance Leakage Current		5		pF	
POWER REQUIREMENTS					
V_{DD}	2.7		3.6	V	All Digital Inputs at 0 or VDD
					DAC Active and Excluding Load Current
I _{DD} (Normal Mode) ⁸					V _{IH} =V _{DD} and V _{IL} =GND
V_{DD} =2.7 V to +3.6 V		0.7	1	mA	Internal Reference Off
V_{DD} =2.7 V to +3.6 V		2	2.5	mA	Internal Reference On
I _{DD} (All Power-Down Modes) ⁹					
V_{DD} =2.7 V to +3.6 V			1	μΑ	V _{IH} =V _{DD} and V _{IL} =GND
POWER EFFICIENCY					
I _{OUT} /I _{DD}		89		%	I _{LOAD} =2 mA, V _{DD} =+5 V

AC CHARACTERISTICS¹

 $(V_{DD} = +2.7 \text{ V to } +3.6 \text{ V}; R_L = 2 \text{ k}\Omega \text{ to GND}; C_L = 200 \text{ pF to GND}; External VREF = Vdd; all specifications } T_{MIN} \text{ to } T_{MAX} \text{ unless otherwise noted})$

Parameter ²	Min	Тур	Max	Unit	B Version ¹ Conditions/Comments
Output Voltage Settling Time		-7F			
AD5666		8	10	μs	1/4 to 3/4 scale settling to ±2LSB
Settling Time for 1LSB Step					-
Slew Rate		1		V/µs	
Digital-to-Analog Glitch Impulse		10		nV-s	1 LSB Change Around Major Carry. See Figure 21.
Reference Feedthrough		100		dB	
Digital Feedthrough		0.5		nV-s	
SDO Feedthrough		4		nV-s	Daisy Chain Mode; SDO Load is 10pF
Digital Crosstalk		0.5		nV-s	
Analog Crosstalk		1		nV-s	
DAC-to-DAC Crosstalk		3		nV-s	
Multiplying Bandwidth		200		kHz	$VREF = 2V \pm 0.1 V p-p.$
Total Harmonic Distortion		-80		dB	VREF = $2V \pm 0.1 V$ p-p. Frequency = $10kHz$
Output Noise Spectral Density		120		nV/√Hz	DAC code=8400 _H , 1kHz
		100		nV/√Hz	DAC code=8400 _H , 10kHz
Output Noise		15		μVр-р	0.1Hz to 10Hz;

NOTES

 $^{}_{1}\text{Guaranteed}$ by design and characterization; not production tested.

²See the Terminology section.

³Temperature range (Y Version): -40°C to +125°C; typical at +25°C.

Specifications subject to change without notice.

TIMING CHARACTERISTICS 1,2,3

(All specifications T_{MIN} to T_{MAX} unless otherwise noted)

	Limit a	t T _{MIN} , T _{MAX}		
Parameter	$V_{DD} = 2.7 \text{ V to } 3.6 \text{ V}$	$V_{DD} = 3.6 \text{ V to } 5.5 \text{ V}$	Unit	Conditions/Comments
t ₁ 1	20	20	ns min	SCLK Cycle Time
t_2	11	9	ns min	SCLK High Time
t_3	9	9	ns min	SCLK Low Time
t ₄	13	13	ns min	SYNC to SCLK Falling Edge Setup Time
t ₅	4	4	ns min	Data Setup Time
t ₆	4	4	ns min	Data Hold Time
t ₇	0	0	ns min	SCLK Falling Edge to SYNC Rising Edge
t ₈	25	20	ns min	Minimum SYNC High Time
t 9	13	13	ns min	SYNC Rising Edge to SCLK Fall Ignore
t ₁₀	0	0	ns min	SCLK Falling Edge to SYNC Fall Ignore
t ₁₁	20	20	ns min	LDAC Pulsewidth Low
t ₁₂	20	20	ns min	SCLK Falling Edge to <i>LDAC</i> Rising Edge
t ₁₃	20	20	ns min	/CLR Pulse Width Low
t ₁₄	0	0	ns min	SCLK Falling Edge to <i>LDAC</i> Falling Edge
t ₁₅ 4,5	20	20	ns max	SCLK Rising Edge to SDO Valid
t ₁₆ ⁵	5	5	ns min	SCLK Falling Edge to SYNC Rising Edge
t ₁₇ ⁵	8	8	ns min	SYNC Rising Edge to SCLK Rising Edge
t ₁₈ ⁵	0	0	ns min	SYNC Rising Edge to LDAC Falling Edge

 $^{^{1}}$ 3Maximum SCLK frequency is 50 MHz at V_{DD} = +3.6 V to +5.5 V and 20 MHz at V_{DD} = +2.7 V to +3.6 V.

Specifications subject to change without notice.

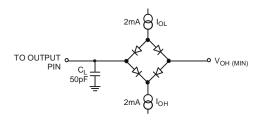


Figure 1. Load Circuit for Digital Output (SDO) Timing Specifications

¹Guaranteed by design and characterization; not production tested.

²All input signals are specified with tr = tf = 1 ns/V (10% to 90% of VDD) and timed from a voltage level of (VIL+ VIH)/2. 3See Figures 2 and 3.

⁴This is measured with the load circuit of Figure 1. t15 determines maximum SCLK frequency in Daisy-Chain mode.

⁵Daisy-chain mode only.

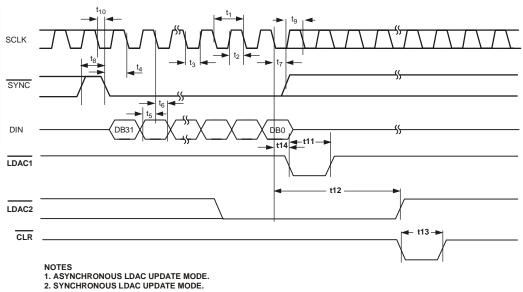


Figure 2. Serial Write Operation

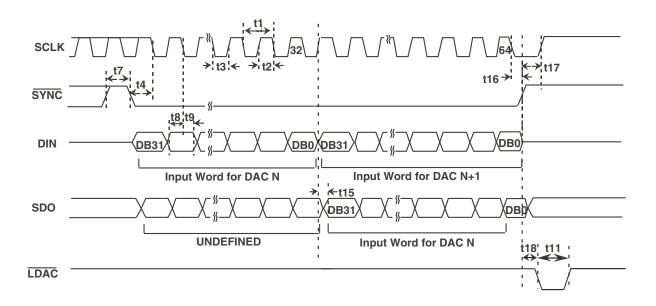


Figure 3. Daisy Chain Timing Diagram

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

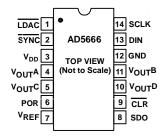


Figure 3. 14-Lead TSSOP (RU-14)

Table 2. Pin Function Descriptions

Pin No.	Mnemonic	Function
1	LDAC	Pulsing this pin low allows any or all DAC registers to be updated if the input registers have new data. This allows simultaneous update of all DAC outputs. Alternatively, this pin can be tied permanently low.
2	SYNC	Active Low-Control Input. This is the frame synchronization signal for the input data. When <i>SYNC</i> goes low, it powers on the SCLK and DIN buffers and enables the input shift register. Data is transferred in on the falling edges of the following 32 clocks. If <i>SYNC</i> is taken high before the 32nd falling edge, the rising edge of <i>SYNC</i> acts as an interrupt and the write sequence is ignored by the device.
3	VDD	Power Supply Input. These parts can be operated from 2.75 V to 5.5 V, and the supply should be decoupled with a 10 μ F capacitor in parallel with a 0.1 μ F capacitor to GND.
4	VOUTA	Analog Output Voltage from DAC A. The output amplifier has rail-to-rail operation.
5	VOUTC	Analog Output Voltage from DAC C. The output amplifier has rail-to-rail operation.
6	POR	Power-On–Reset pin. Tying this pin to GND powers on part to 0V. Tying to V_{DD} powers on part to midscale.
7	Vrefin/Vrefout	The AD5666 has a common reference input/reference output Pin. When the internal reference is selected this is the reference output pin. When using an external reference, this is the reference input pin. The default for this pin is a reference input.
8	SDO	Serial Data Output. Can be used for daisy-chaining a number of these devices together or for reading back the data in the shift register for diagnostic purposes. The serial data is transferred on the rising edge of SCLK and is valid on the falling edge of the clock.
9	CLR	Asynchronous Clear Input. The CLR input is falling edge sensitive and Active low. While CLR is low all LDAC pulses are ignored. When CLR is activated, all channels are updated with the data contained in the CLR code register - Zero, midscale, or fullscale Default setting clears the output to 0V.
10	VOUTD	Analog Output Voltage from DAC D. The output amplifier has rail-to-rail operation.
11	VOUTB	Analog Output Voltage from DAC B. The output amplifier has rail-to-rail operation.
12	GND	Ground Reference Point for All Circuitry on the Part.
13	DIN	Serial Data Input. This device has a 32-bit shift register. Data is clocked into the register on the falling edge of the serial clock input.
14	SCLK	Serial Clock Input. Data is clocked into the input shift register on the falling edge of the serial clock input. Data can be transferred at rates up to 50 MHz.

ABSOLUTE MAXIMUM RATINGS

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

 $(T_A = +25^{\circ}C \text{ unless otherwise noted})$

Parameter	Rating
V _{DD} to GND	-0.3 V to +7 V
Digital Input Voltage to GND	$-0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$

VOUT TO GND	$-0.3 \text{ V to V}_{DD} + 0.3 \text{ V}$
Operating Temperature Range	
Industrial (B Version)	-40°C to +105°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature (T _J Max)	+150°C
TSSOP Package	
Power Dissipation	$(T_J Max-T_A)/\theta_{JA}$
θ_{JA} Thermal Impedance	150.4°C/W
Lead Temperature, Soldering	
Vapor Phase (60 sec)	+215°C
Infrared (15 sec)	+220°C

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



TERMINOLOGY

Relative Accuracy

For the DAC, relative accuracy or Integral Nonlinearity (INL) is a measure of the maximum deviation, in LSBs, from a straight line passing through the endpoints of the DAC transfer function. A typical INL vs. code plot can be seen in Figure 2.

Differential Nonlinearity

Differential Nonlinearity (DNL) is the difference between the measured change and the ideal 1 LSB change between any two adjacent codes. A specified differential nonlinearity of ± 1 LSB maximum ensures monotonicity. This DAC is guaranteed monotonic by design. A typical DNL vs. code plot can be seen in Figure 3.

Offset Error

Offset error is a measure of the difference between VOUT (actual) and VOUT (ideal) expressed in mV in the linear region of the transfer function. Offset error is measured on the AD5666 with Code 512 loaded into the DAC register.

This is a measure of the offset error of the DAC and the output amplifier (see Figures 2 and 3). It can be negative or positive, and is expressed in mV.

Zero-Code Error

Zero-code error is a measure of the output error when zero code

(0000Hex) is loaded to the DAC register. Ideally the output should be 0 V. The zero-code error is always positive in the AD5666 because the output of the DAC cannot go below 0 V. It is due to a combination of the offset errors in the DAC and output amplifier. Zero-code error is expressed in mV. A plot of zero-code error vs. temperature can be seen in Figure 6.

Gain Error

This is a measure of the span error of the DAC. It is the deviation in slope of the DAC transfer characteristic from ideal expressed as a percent of the full-scale range.

Zero-Code Error Drift

This is a measure of the change in zero-code error with a change in temperature. It is expressed in $\mu V/^{\circ}C$.

Gain Error Drift

This is a measure of the change in gain error with changes in temperature. It is expressed in (ppm of full-scale range)/°C.

Full-Scale Error

Full-scale error is a measure of the output error when full-scale code (FFFF Hex) is loaded to the DAC register. Ideally the output should be VDD – 1 LSB. Full-scale error is expressed in percent of full-scale range. A plot of full-scale error vs. temperature can be seen in Figure 6.

Total Unadjusted Error

Total Unadjusted Error (TUE) is a measure of the output error

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taking the various offset and gain errors into account. A typical TUE vs. code plot can be seen in Figure 4.

Digital-to-Analog Glitch Impulse

Digital-to-analog glitch impulse is the impulse injected into the analog output when the input code in the DAC register changes state. It is normally specified as the area of the glitch in nV secs and is measured when the digital input code is changed by 1 LSB at the major carry transition (7FFF Hex to 8000 Hex). See Figure 19.

DC Power Supply Rejection Ratio (PSRR)

This indicates how the output of the DAC is affected by changes in the supply voltage. PSRR is the ratio of the change in VOUT to a change in VDD for full-scale output of the DAC. It is measured in dB. VREF is held at 2 V and VDD is varied $\pm 10\%$.

DC Crosstalk

This is the dc change in the output level of one DAC in response to a change in the output of another DAC. It is measured with a full-scale output change on one DAC while monitoring another DAC kept at midscale. It is expressed in μV .

Reference Feedthrough

This is the ratio of the amplitude of the signal at the DAC output to the reference input when the DAC output is not being updated (i.e., *LDAC* is high). It is expressed in dB.

Digital Feedthrough

Digital feedthrough is a measure of the impulse injected into the analog output of a DAC from the digital input pins of the device, but is measured when the DAC is not being written to (*SYNC* held high). It is specified in nV-s and is measured with a fullscale change on the digital input pins, i.e., from all 0s to all 1s and vice versa.

Digital Crosstalk

This is the glitch impulse transferred to the output of one DAC at midscale in response to a full-scale code change (all 0s to all 1s and vice versa) in the input register of another DAC. It is measured in standalone mode and is expressed in nV-s.

Analog Crosstalk

This is the glitch impulse transferred to the output of one DAC due to a change in the output of another DAC. It is measured by loading one of the input registers with a full-scale code change (all 0s to all 1s and vice versa) while keeping *LDAC* high. Then pulse *LDAC* low and monitor the output of the DAC whose digital code was not changed. The area of the glitch is expressed in nV-s.

DAC-to-DAC Crosstalk

This is the glitch impulse transferred to the output of one DAC due to a digital code change and subsequent output change of another DAC. This includes both digital and analog crosstalk. It is measured by loading one of the DACs with a full-scale code change (all 0s to all 1s and vice versa) with *LDAC* low and monitoring the output of another DAC. The energy of the glitch is expressed in nV-s.

Multiplying Bandwidth

The amplifiers within the DAC have a finite bandwidth. The multiplying bandwidth is a measure of this. A sine wave on the reference (with full-scale code loaded to the DAC) appears on the output. The multiplying bandwidth is the frequency at which the output amplitude falls to 3 dB below the input.

Total Harmonic Distortion

This is the difference between an ideal sine wave and its attenuated version using the DAC. The sine wave is used as the reference for the DAC, and the THD is a measure of the harmonics present on the DAC output. It is measured in dB.

AD5666-TYPICAL PERFORMANCE CHARACTERISTICS

TBD

Figure 2. Typical INL Plot

Figure 4. Typical INL Plot

TBD

Figure 3. Typical DNL Plot

Figure 5. Typical DNL Plot

TBD

Figure 4. Typical Total Unadjusted Error Plot

Figure 6. Typical Total Unadjusted Error Plot

TBD

Figure 5. INL Error and DNL Error vs. Temperature

Figure 7. INL Error and DNL Error vs. Temperature

TBD

Figure 6. Zero-Scale Error and Full-Scale Error vs. Temperature

Figure 8. Zero-Scale Error and Full-Scale Error vs. Temperature

TBD

Figure 7. I_{DD} Histogram with V_{DD} = 3 V and V_{DD} = 5 V

Figure 9. I_{DD} Histogram with V_{DD} =3V and V_{DD} =5V

TBD

Figure 8. Source and Sink Current Capability with V_{DD} = 3 V

Figure 10. Source and Sink Current Capability with $V_{DD}=3V$

TBD

Figure 9. Source and Sink Current Capability with $V_{DD} = 5 \text{ V}$

Figure 11. Source and Sink Current Capability with $V_{DD}=5 V$

TBD

Figure 10. Supply Current vs. Code

Figure 12. Supply Current vs. Code

TBD

Figure 11. Supply Current vs. Temperature

Figure 13. Supply Current vs. Temperature

TBD

Figure 12. Supply Current vs. Supply Voltage

Figure 14. Supply Current vs. Supply Voltage

TBD

Figure 13. Power-Down Current vs. Supply Voltage

Figure 15. Power-Down Current vs. Supply Voltage

TBD

Figure 14. Supply Current vs. Logic Input Voltage

Figure 16. Supply Current vs. Logic Input Voltage

TBD

Figure 15. Full-Scale Settling Time

Figure 17. Full-Scale Settling Time

TBD

Figure 16. Half-Scale Settling Time

Figure 18. Half-Scale Settling Time

TBD

Figure 17. Power-On Reset to 0 V

Figure 19. Power-On Reset to 0V

TBD

Figure 18. Exiting Power-Down (800 Hex Loaded)

Figure 20. Exiting Power-Down (800 Hex Loaded)

TBD

Figure 19. Digital-to-Analog Glitch Impulse

Figure 21. Digital-to-Analog Glitch Impulse

GENERAL DESCRIPTION

D/A Section

The AD5666 DAC is fabricated on a CMOS process. The architecture consists of a string DAC followed by an output buffer amplifier. The parts include an internal 1.25/2.5V, 10ppm/°C reference with an internal gain of two. Figure 22 shows a block diagram of the DAC architecture.

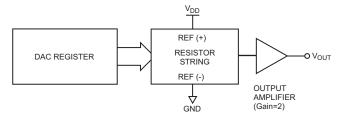


Figure 22. DAC Architecture

Since the input coding to the DAC is straight binary, the ideal output voltage is given by:

$$V_{OUT} = Vrefin \times \left(\frac{D}{2^{\wedge}N}\right)$$

when using an external reference;

$$V_{OUT} = 2 * Vrefout \times \left(\frac{D}{2^{\hat{}}N}\right)$$

when using the internal reference;

where D = decimal equivalent of the binary code that is loaded to the DAC register;

0 - 65535 for AD5666 (16 bit)

N = the DAC resolution

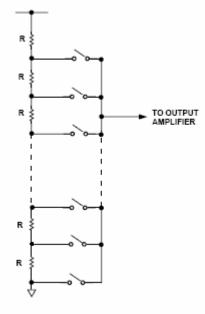


Figure 21. Resistor String

Figure 23. Resistor String

RESISTOR STRING

The resistor string section is shown in Figure 23. It is simply a string of resistors, each of value R. The code loaded to the DAC register determines at which node on the string the voltage is tapped off to be fed into the output amplifier. The voltage is tapped off by closing one of the switches connecting the string to the amplifier. Because it is a string of resistors, it is guaranteed monotonic.

INTERNAL REFERENCE

The AD5666 has an on-chip reference with an internal gain of two. The AD5666-1 has a 1.25V 10ppm/°C max reference giving a fullscale output of 2.5V and the AD5666-2 has a 2.5V 10ppm/°C max reference giving a fullsclae output of 5V. The on-board reference is off at power-up allowing the use of an external reference. The internal reference is enabled via a write to a control register

The internal reference associated with each part is available at the V_{REFOUT} pin. A buffer is required if the reference output is used to drive external loads

When using the internal reference, it is recommended that a 100nF capacitor is placed between reference output and GND for reference stability.

OUTPUT AMPLIFIER

The output buffer amplifier is capable of generating rail-to-rail voltages on its output which gives an output range of 0 V to $V_{\text{DD}}.$ It is capable of driving a load of 2 $k\Omega$ in parallel with 1000

pF to GND. The source and sink capabilities of the output amplifier can be seen in Figure 10 and Figure 11. The slew rate is 1 V/ μ s with a half-scale settling time of 8 μ s with the output unloaded.

SERIAL INTERFACE

The AD5666 has a three-wire serial interface (SYNC, SCLK and DIN), which is compatible with SPI, QSPI and MICROWIRE interface standards as well as most DSPs. See Figure 2 for a timing diagram of a typical write sequence.

The write sequence begins by bringing the $\overline{\text{SYNC}}$ line low. Data from the DIN line is clocked into the 32-bit shift register on the falling edge of SCLK. The serial clock frequency can be as high as 50 MHz, making the AD5666 compatible with high speed DSPs. On the 32nd falling clock edge, the last data bit is clocked in and the programmed function is executed (i.e., a change in DAC register contents and/or a change in the mode of operation). At this stage, the SYNC line may be kept low or be brought high. In either case, it must be brought high for a minimum of 50 ns before the next write sequence so that a falling edge of SYNC can initiate the next write sequence. Since the \overline{SYNC} buffer draws more current when $V_{IN} = 2V$ than it does when $V_{IN} = 0.8 \text{ V}$, $\overline{\text{SYNC}}$ should be idled low between write sequences for even lower power operation of the part. As is mentioned above, however, it must be brought high again just before the next write sequence.

Input Shift Register

The input shift register is 32 bits wide (see Figure 24). The first five bits are "don't cares." The next four bits are the Command bits C3-C0, (see Table 1) followed by the 4-bit DAC address A3-A0, (see Table 2) and finally the 16-bit data word. The data word comprises the 16- bit input code followed by 4 don't care bits for the AD5666. See figure 24. These data bits are transferred to the DAC register on the 32nd falling edge of SCLK.

Daisy-Chaining

For systems that contain several DACs, or where the user wishes to read back the DAC contents for diagnostic purposes, the SDO pin may be used to daisy-chain several devices together and provide serial readback.

The the daisy chain mode is enabled through a software executable DCEN Setup function, Command 1000 is reserved for this DCEN Setup function, see Table 3. The daisy chain mode is software-programmable by setting a bit (DB1) in the DCEN Setup register. The default setting is stand-alone mode where bit DCEN =0. Table 4 shows how the state of the bits corresponds to the mode of operation of the device. input shift register when SYNC is low. If more than 32 clock pulses are applied, the data ripples out of the shift register and appears on the SDO line. This data is clocked out on the rising edge of SCLK and is valid on the falling edge. By connecting this line to the DIN input on the next DAC in the chain, a multi-DAC interface is constructed. Thirty-two clock pulses are required for each DAC in the system. Therefore, the total number of clock cycles must equal 32N, where N is the total number of devices in the chain. When the serial transfer to all devices is complete, SYNC should be taken high. This prevents any further data from being clocked into the input shift register.

A continuous SCLK source may be used if it can be arranged that SYNC is held low for the correct number of clock cycles. Alternatively, a burst clock containing the exact number of clock cycles may be used and SYNC may be taken high some time later.

When the transfer to all input registers is complete, a common *LDAC* signal updates all DAC registers and all analog outputs are updated simultaneously.

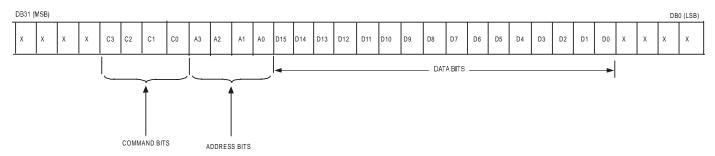


Figure 24a AD5666. Input Register Contents

Comr	nand			
С3	C2	C1	C0	
0	0	0	0	Write to Input Register n
0	0	0	1	Update DAC Register n
0	0	1	0	Write to Input Register n, Update All (Software LDAC)
0	0	1	1	Write to and Update DAC channel n
0	1	0	0	Power Down DAC (Power-up)
0	1	0	1	Load Clear Code Register
0	1	1	0	Load LDAC Register
0	1	1	1	Reset (Power-on-Reset)
1	0	0	0	DCEN/REF Setup Register
1	0	0	1	Reserved
*	*	*	*	Reserved
1	1	1	1	Reserved

Table 1. Command Definition

ADDR	ESS (n)			
A3	A2	A1	A0	
0	0	0	0	DAC A
0	0	0	1	DAC B
0	0	1	0	DAC C
0	0	1	1	DAC D
1	1	1	1	All DACs

Table2. Address Command

SYNC INTERRUPT

In a normal write sequence, the $\overline{\text{SYNC}}$ line is kept low for at least 32 falling edges of SCLK and the DAC is updated on the 32nd falling edge. However, if $\overline{\text{SYNC}}$ is brought high before the 32nd falling edge this acts as an interrupt to the write sequence. The shift register is reset and the write sequence is seen as invalid. Neither an update of the DAC register contents or a change in the operating mode

occurs—see Figure 25.

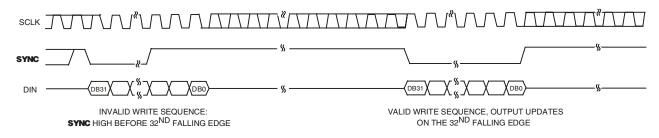


Figure 25. SYNC Interrupt Facility

INTERNAL REFERENCE SETUP

The on-board reference is off at power-up by default. This allows the use of an external reference if the application requires it. The AD5666-1 has a 1.25V 10ppm/°C max reference giving a fullscale output of 2.5V and the AD5666-2 have a 2.5V 10ppm/°C max reference giving a fullscale output of 5V. The on-board reference can be turned on/off by a user programmable REF Setup register by setting the bit DB0 high or low, see Table 3. Command 1000 is reserved for this Internal REF Setup command, see Table 1. Table 4 shows how the state of the bits in the Input Shift Register corresponds to the mode of operation of the device.

DCEN/REF Setu				
DCEN (DB1)	REF (DB0)	Action		
0	0	Stand-Alone Mode – Ref Off		
0	1	Stand-Alone Mode – Ref On		
1	0	DCEN Mode – Ref Off		
1	1	DCEN Mode – Ref On		

Table 3. Daisy Chain Enable /Reference Set-up Register

MSB											
DB31 - DB28	DB27	DB26	DB25	DB24	DB23	DB22	DB21	DB20	DB2- DB19	DB1	DB0
X	1	0	0	0	X	х	X	х	х	1/0	1/0
Don't Cares	COMMAND BITS (C3-C0)				ADDRESS	Don't Cares	DCEN/				

Table 4. 32-Bit Input Shift Register Contents for Daisy Chain Enable and Reference Setup Function

POWER-ON-RESET

The AD5666 family contains a power-on-reset circuit that controls the output voltage during power-up. By connecting the POR pin low the DAC output powers up to zero volts and by connecting the POR pin high the DAC output powers up to midscale. The output remains there until a valid write sequence is made to the DAC. This is useful in applications where it is important to know the state of the output of the DAC while it is in the process of powering up.

There is also a software executable Reset function that will reset the DAC to the Power-on -Reset code. Command 111 is reserved for this Reset function, see Table 1.

Any events on LDAC or CLRduring power-on-reset are ignored.

POWER-DOWN MODES

The AD5666 contains four separate modes of operation. Command 0100 is reserved for the Power-Down function. See Table 1. These modes are software-programmable by setting two bits (DB19 and DB18) in the control register. Table 3 shows how the state of the bits corresponds to the mode of operation of the device. Any or all DACs, (DacD to DacA) may be powered down to the selected mode by setting the corresponding 4 bits (DB7,6,1,0) to a "1". See Table 6 for contents of the Input Shift Register during power down/up operation.

When both bits are set to 0, the part works normally with its normal power consumption of 250 μ A at 5 V. However, for the three power-down modes, the supply current falls to 200 nA at 5 V (50 nA at 3 V). Not only does the supply current fall but the output stage is also internally switched from the output of the amplifier to a resistor network of known values. This has the advantage that the output impedance of the part is known while the part is in power-down mode. There are three different options. The output is connected internally to GND through a 1 k Ω resistor, a 100 k Ω resistor or it is left open-circuited (Three-State). The output stage is illustrated in figure 24.

The bias generator, the output amplifier, the resistor string and other associated linear circuitry are all shut down when the power-down mode is activated. The internal reference is powered-down only when all channels are powered down. However, the contents of the DAC register are unaffected when in power-down. The time to exit power-down is typically (2.5 μ s for $V_{DD} = 5 V$ and 5 μ s for $V_{DD} = 3 V$)???. See Figure 20 for a plot.

Any combination of DACs can be powered up by setting PD1 and PD0 to "0" (normal operation). Output powers-up to value in input register (/LDAC Low) or to value in DAC register before Power-Down (/LDAC High).

DB9	DB8	Operating Mode
0	0	Normal Operation
		Power Down Modes
0	1	1 kΩ to GND
1	0	100 kΩ to GND
1	1	Three State

Table 3. Modes of Operation for the AD5666

MSB																LSB
DB31 - DB28	DB27	DB26	DB25	DB24	DB23	DB22	DB21	DB20	DB10— DB19	DB9	DB8	DB4- DB7	DB3	DB2	DB1	DB0
х	0	1	0	0	х	х	х	х	х	PD1	PD0	X	DacD	DacC	DacB	DacA
Don't Cares	СОММ	AND BITS	(C2-C0)	I	ADDRE: Don't co	SS BITS (A. ares	3 – <i>A0)</i>	<u> </u>	Don't Cares	Power Down		Don't Cares	Power Dow Set Bit to a '		nel Selecti	on –

Table 6. 32-Bit Input Shift Register Contents of Power Up/Down Function

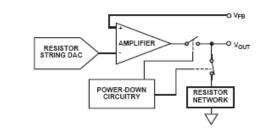


Figure 24. Output Stage During Power-Down

CLEAR CODE REGISTER

The AD5666 has a hardware $\overline{\text{CLR}}$ pin that is an asynchronous Clear Input. The $\overline{\text{CLR}}$ input is falling edge sensitive and active low. Bringing the $\overline{\text{CLR}}$ line low clears the contents of the DAC registers to the data contained in the user-configurable $\overline{\text{CLR}}$ register and sets the analog outputs accordingly. This function can be used in system calibration to load zero scale, midscale or full scale to all channels together. These clear code values are user-programmable by setting two bits (DB1 and DB0) in the control register. Default setting clears the outputs to 0V. Command 0101 is reserved for loading the Clear Code Register. See Table1

The part will exit Clear code mode on the 32^{nd} falling edge of the next write to the part. If \overline{CLR} is activated during a write sequence the write will be aborted.

See Table 7 for contents of the Input Shift Register during the loading Clear Code Register operation. CLR

Clear Code Regis		
CR1	CR0	Clears to code
0	0	0000h
0	1	8000h
1	0	FFFFh
1	1	No operation

Table 6. Clear Code Register

MSB											LSB
DB31 - DB28	DB27	DB26	DB25	DB24	DB23	DB22	DB21	DB20	DB2- DB19	DB1	DB0
Х	0	1	0	1	х	Х	х	Х	х	1/0	1/0
Don't Cares	COMMANI	D BITS (C2-C0)	,	,	ADDRESS E	BITS (A3 – A0)		•	Don't Cares	Clear Co Register CR0)	

Table 7. 32-Bit Input Shift Register Contents Clear Code Function

LDAC FUNCTION

The outputs of all DACs may be updated simultaneously using the hardware /LDAC pin.

Synchronous $\overline{\text{LDAC}}$: The DAC registers are updated after new data is read in on the falling edge of the 32nd SCLK pulse. $\overline{\text{LDAC}}$ can be

Preliminary Technical Data

permanently low or pulsed as in Figure 1.

Asynchronous $\overline{\text{LDAC}}$: The outputs are not updated at the same time that the input registers are written to. When $\overline{\text{LDAC}}$ goes low, the DAC registers are updated with the contents of the input register.

Alternatively, a software $\overline{\text{LDAC}}$ function is available. Command 0011 is reserved f or this software $\overline{\text{LDAC}}$ function - write to input register n and update all.

An \overline{LDAC} register gives the user extra flexibility and control over the hardware \overline{LDAC} pin. This register allows the user to select which combination of channels to simultaneously update when the hardware \overline{LDAC} pin is executed. Setting the \overline{LDAC} bit register to a "0" for a DAC channel means that this channels' update will be controlled by the \overline{LDAC} pin. If this bit is set to a "1" then this channel will synchronously update, that is the DAC register is updated after new data is read in regardless of the state of the /LDAC pin It effectively sees the \overline{LDAC} pin as being pulled low. See Table 9 for the \overline{LDAC} register mode of operation. This flexibility is useful in applications where the user wants to simultaneously update select channels while the rest of the channels are synchronously updating

Writing to the DAC using command 0110,loads the 4-bit /LDAC register (DB3-DB0) The default for each channel is "0" ie LDAC pin works normally. Setting the bits to a "1" means the \overline{DAC} channel will be updated regardless of the state of the \overline{LDAC} pin. See Table 10 for contents of the Input Shift Register during the load \overline{LDAC} register mode of operation.

Load DAC Register	Load DAC Register						
DBO)	LDAC PIN	LDAC Operation					
0	1/0	Determined by LDAC pin					
1	x – Don't Care	DAC channels will update, overwriting the LDACpin. DAC channels see LDAC as 0					

Table 5. LDAC Overwrite Definition

MSB										LSB			
DB31 - DB28	DB27	DB2 6	DB2 5	DB2 4	DB2 3	DB2 2	DB2 1	DB2 0	DB4 -DB19	DB3	DB2	DB1	DB0
х	0	1	1	0	х	х	х	х	×	DacD	DacC	DacB	DacA
Don't Cares	COMMA	AND BITS (C2-C0)	•	ADDRES Don't co	SS BITS (A3 ares	3 – A0)	•	Don't Cares	Setting LDAC	bit to "1" overv	vrites /LD	AC pin

Table 8. 32-Bit Input Shift Register Contents for /LDAC Overwrite Function

POWER SUPPLY BYPASSING AND GROUNDING

When accuracy is important in a circuit it is helpful to carefully consider the power supply and ground return layout on the board. The printed circuit board containing the AD5666 should have separate analog and digital sections, each having its own area of the board. If the AD5666 is in a system where other devices require an AGND to DGND connection, the connection should be made at one point only. This ground point should be as close as possible to the AD5666.

The power supply to the AD5666 should be bypassed with 10 μF and 0.1 μF capacitors. The capacitors should be physically as close as possible to the device with the 0.1 μF capacitor ideally right up against the device. The 10 μF capacitors are the tantalum bead type. It is important that the 0.1 μF capacitor has low Effective Series Resistance (ESR) and Effective Series Inductance (ESI), e.g., common ceramic types of capacitors.

This 0.1 μF capacitor provides a low impedance path to ground for high frequencies caused by transient currents due to internal logic switching.

The power supply line itself should have as large a trace as possible to provide a low impedance path and reduce glitch effects on the supply line. Clocks and other fast switching digital signals should be shielded from other parts of the board by digital ground. Avoid crossover of digital and analog signals if possible. When traces cross on opposite sides of the board, ensure that they run at right angles to each other to reduce feedthrough effects through the board. The best board layout technique is the microstrip technique where the component side of the board is dedicated to the ground plane only and the signal traces are placed on the solder side. However, this is not always possible with a two-layer board.

OUTLINE DIMENSIONS

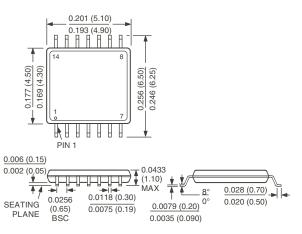


Figure 26. 14-Thin Shrink Small Outline Package [TSSOP] (RU-14) Dimensions shown in millimeters

ORDERING GUIDE

Model	Bit	Internal Reference	Package Option1
AD5666ARUZ-2	16	2.5V	RU-14

¹ Thin Shrink Small Outline Package (TSSOP)



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